



## HY70N06

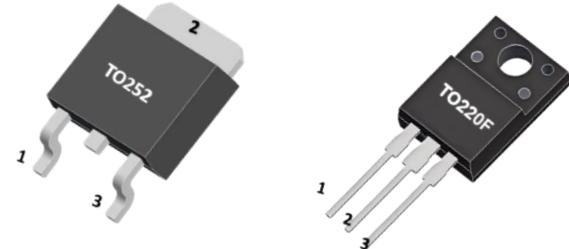
N-CHANNEL POWER MOSFET

### 70A, 60V N-CHANNEL ENHANCEMENT MODE POWER MOSFET

#### ■ DESCRIPTION

The HY70N06A is N-channel enhancement mode power field effect transistors with stable off-state characteristics, fast switching speed, low thermal resistance, usually used at telecom and computer application.

The HY70N06A meet the ROHS and Green Product requirement with full function reliability approved.



#### ■ FEATURES

- \* Good stability and uniformity with high EAS
- \* Excellent package for good heat dissipation
- \* High density cell design for ultra low Rdson
- \* Special process technology for high ESD capability
- \* Fully characterized avalanche voltage and current

#### ■ APPLICATION

- \* Power switching application
- \* Hard switched and high frequency circuits
- \* Uninterruptible power supply

#### ■ MARKING



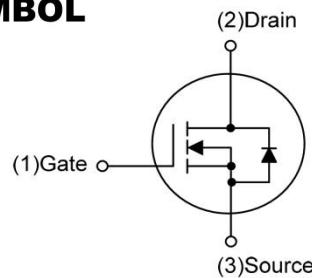
: HY LOGO

HY70N06A=Device Code

XXXX=Date Code

Solid Dot=Green molding compound

#### ■ SYMBOL



#### ■ ABSOLUTE MAXIMUM RATINGS(TA=25°C, unless otherwise specified.)

SYMBOL	PARAMETER	VALUE	UNIT
<b>VDSS</b>	Drain-Source Voltage	60	V
<b>VGSS</b>	Gate-Source Voltage	$\pm 20$	V
<b>ID</b>	Continuous Drain Current	70	A
<b>IDM</b>	Pulsed Drain Current (Note 2)	140	A
<b>EAS</b>	Avalanche Energy      Single Pulsed (Note 3)	165	mJ
<b>dv/dt</b>	Peak Diode Recovery dv/dt (Note 4)	2.1	V/ns
<b>PD</b>	Power Dissipation (Note 1)	TO-220F	36
		TO-252	55
<b>Tj</b>	Junction temperature	+150	°C
<b>Tstg</b>	Operation and Storage Temperature	-55~+150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repeatability rating: pulse width limited by junction temperature.

3. L=0.1mH, IAS=57.5A, VDD=25V, RG=20Ω, Starting Tj=25°C.

4. Isd≤48A, di/dt≤300A/μs, VDD≤BVdss, Starting Tj=25°C.



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### ■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS		UNIT	
Junction to Ambient	TO-220F	$\theta_{JA}$	62.5		°C/W	
	TO-252		110			
Junction to Case	TO-220F	$\theta_{JC}$	3.47		°C/W	
	TO-252(Note 2)		2.2			

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

### ■ ELECTRICAL CHARACTERISTICS (TA=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BVDSS	VGS=0V, ID=250μA	60			V
Drain-Source Leakage Current	IdSS	VDS=60V, VGS=0V			1	μA
Gate- Source Leakage Current	IGSS	VGS=±20V, VDS=0V			±100	nA
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	VGS(TH)	VDS=VGS , ID=250μA	2.0		4.0	V
Static Drain-Source On-State Resistance	RDS(ON)	VGS=10V, ID=35A			12	mΩ
<b>DYNAMIC CHARACTERISTICS</b>						
Input Capacitance	Ciss	VDS=25V, VGS=0V, f= 1.0MHz		3650		pF
Output Capacitance	Cooss			330		
Reverse Transfer Capacitance	Crss			286		
<b>SWITCHING CHARACTERISTICS</b>						
Total Gate Charge	QG	VDS=48V,VGS= 10V, ID=70A IG=1mA (Note1, 2)		90		nC
Gate-Source Charge	QGS			16		
Gate-Drain Charge	QGD			25		
Turn-on delay time	td(on)	VDD=30V, ID=70A VGS=10V,RG=3Ω (Note1, 2)		16		ns
Turn-on rise time	tr			18		
Turn-off delay time	td(off)			60		
Turn-off fall time	tf			24		
<b>DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS</b>						
Maximum Continuous Drain-Source Diode Forward Current	Is				70	A
Maximum Pulsed Drain-Source Diode Forward Current	ISM				140	A
Drain-source diode forward voltage	VSD	Is=70A, VGS=0V			1.4	V
Reverse Recovery Time	trr	VGS=0V, Is=30A dI/dt=100A/μs		45		ns
Reverse Recovery Charge	Qrr			50		

Notes:

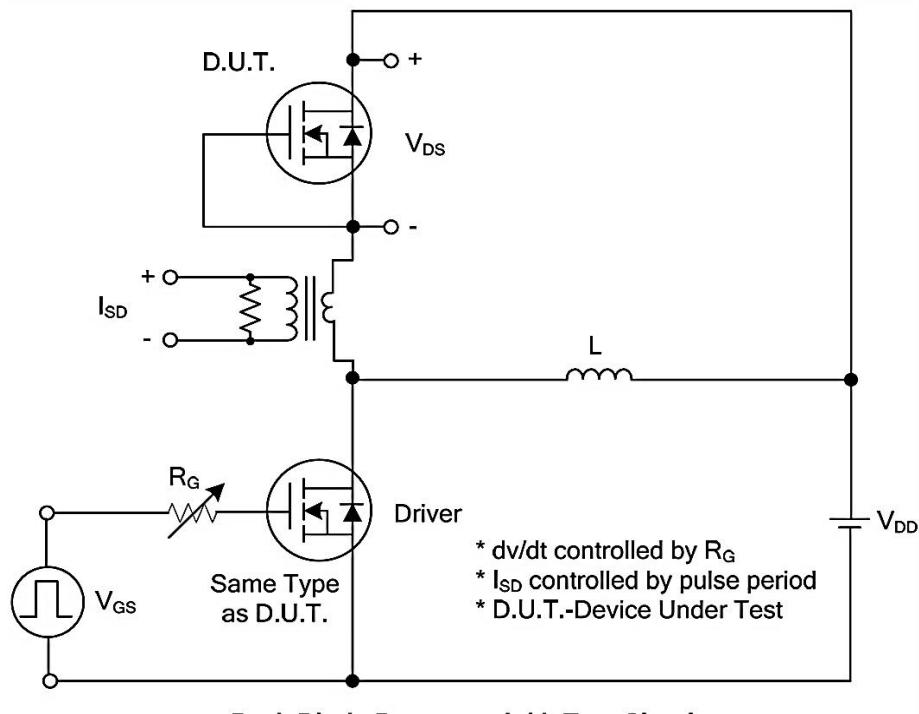
1. Pulse Test: Pulse Width≤300μs, Duty Cycle≤2%.
2. Essentially independent of operating temperature.



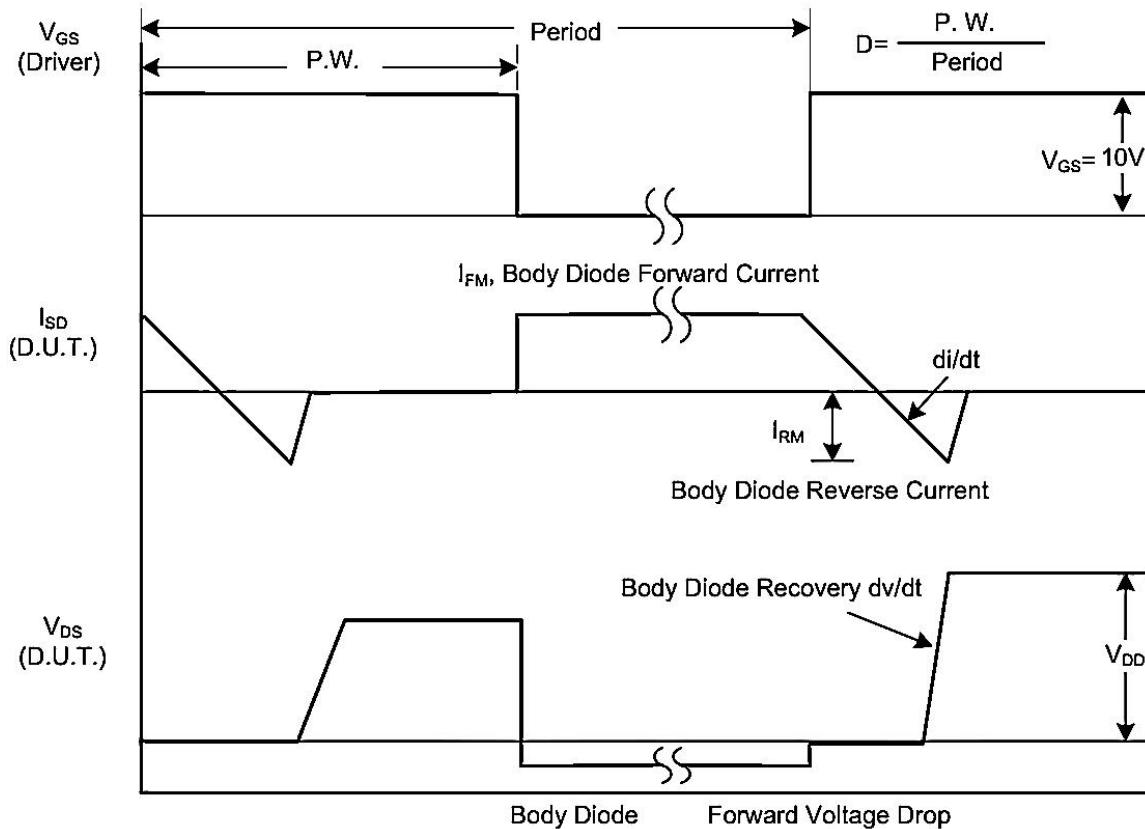
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■ TEST CIRCUITS AND WAVEFORMS



Peak Diode Recovery dv/dt Test Circuit



1B Peak Diode Recovery dv/dt Waveforms



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■ TEST CIRCUITS AND WAVEFORMS(Con.t)

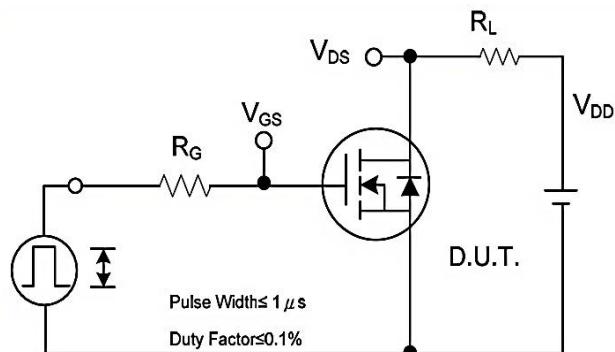


Fig. 2A Switching Test Circuit

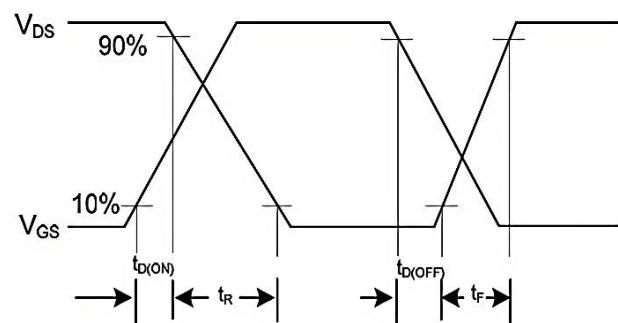


Fig. 2B Switching Waveforms

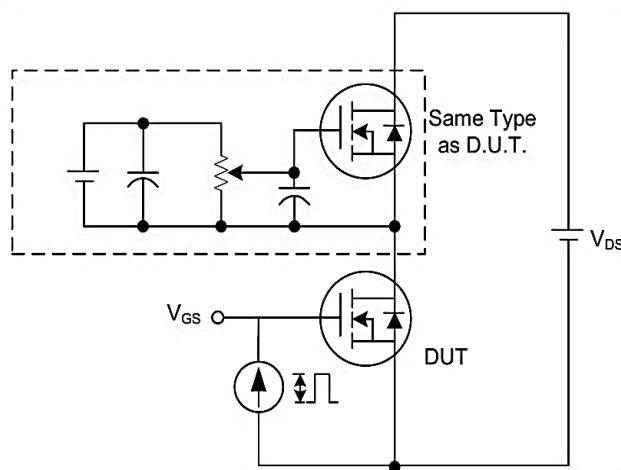


Fig. 3A Gate Charge Test Circuit

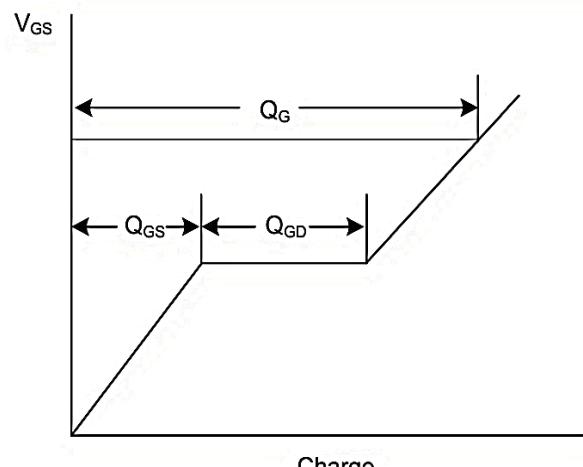


Fig. 3B Gate Charge Waveform

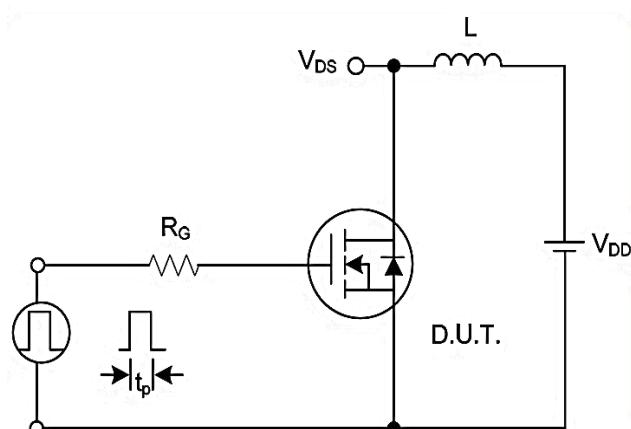


Fig. 4A Unclamped Inductive Switching Test Circuit

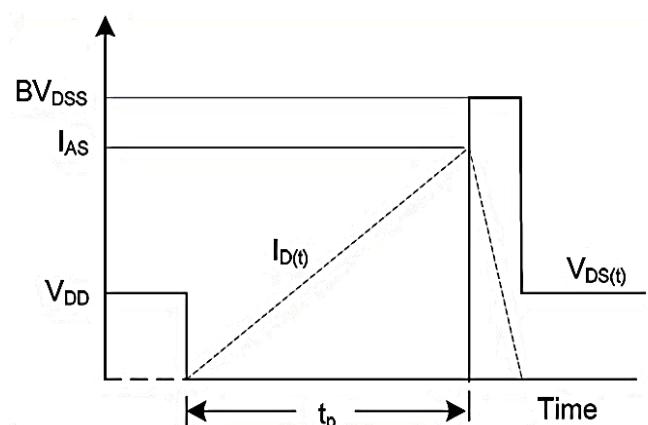


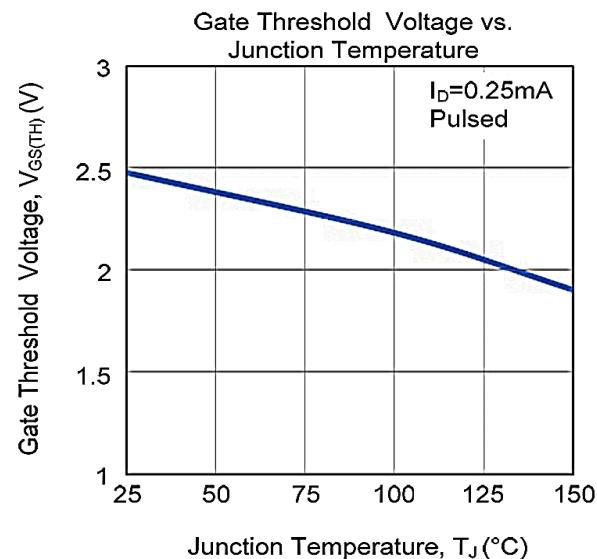
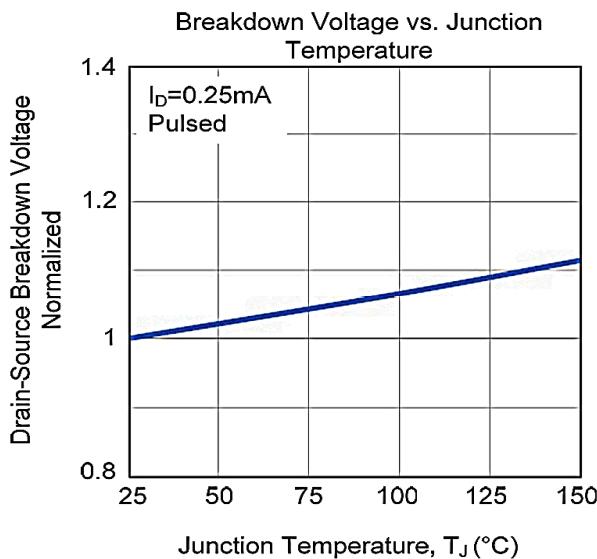
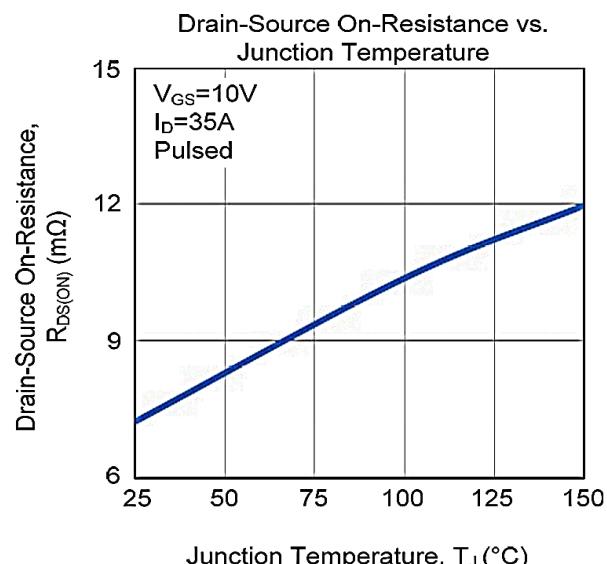
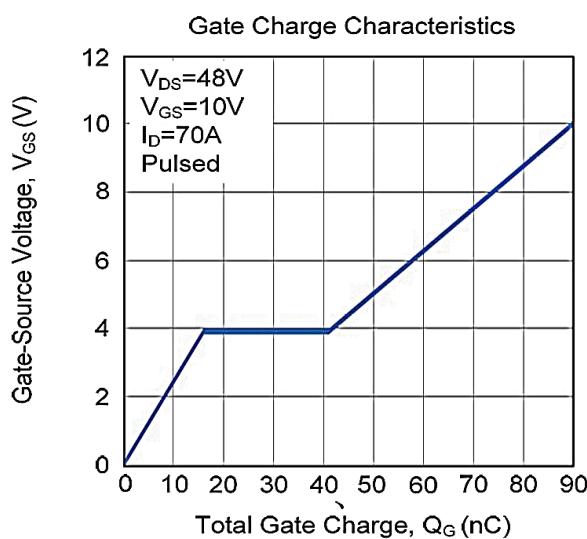
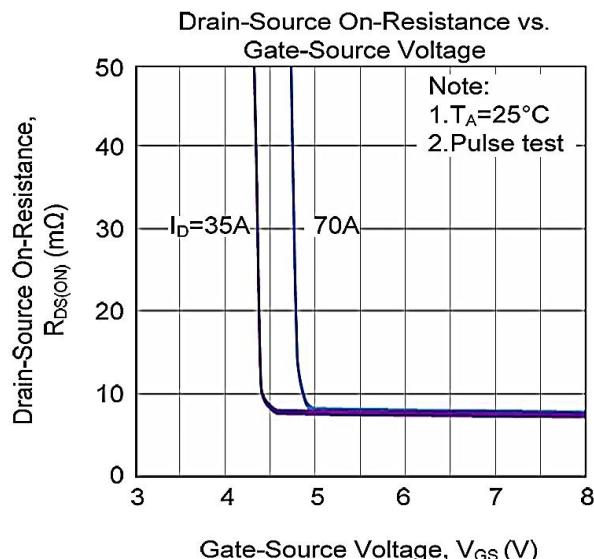
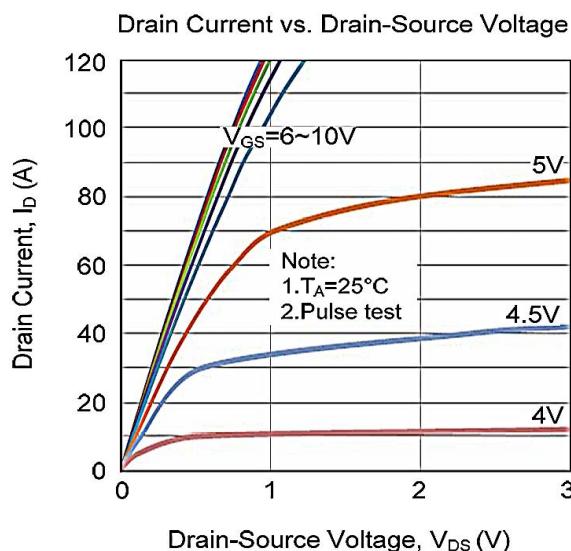
Fig. 4B Unclamped Inductive Switching Waveforms



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■ TYPICAL CHARACTERISTICS(1)

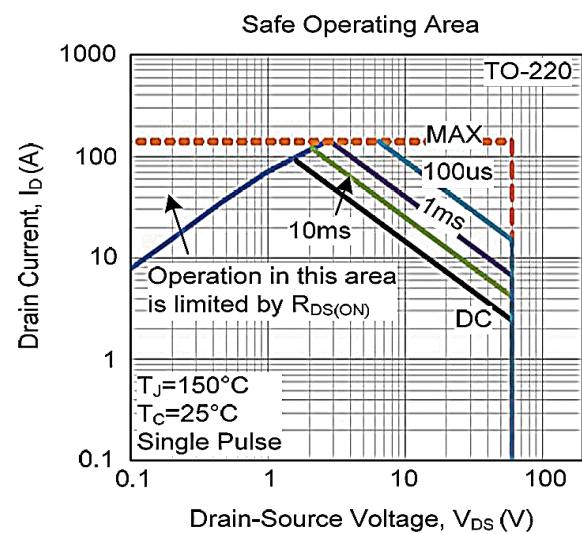
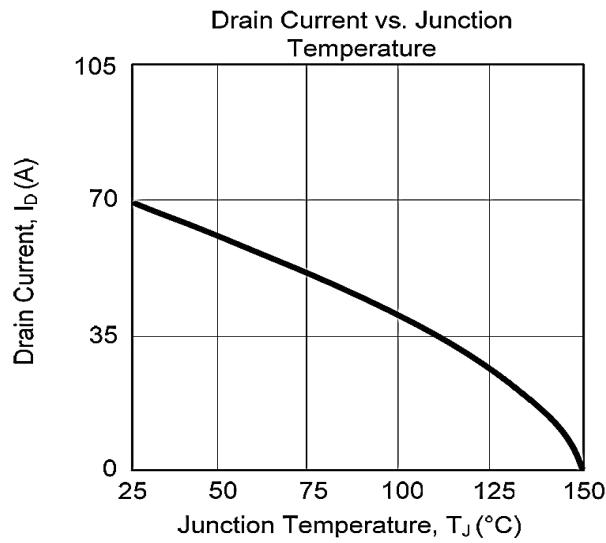
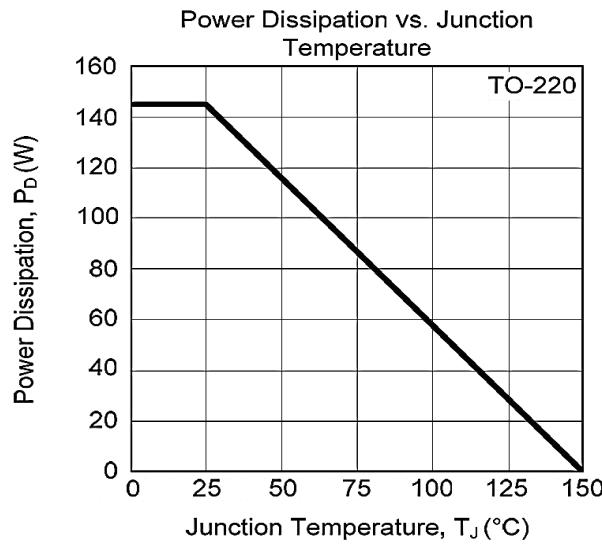
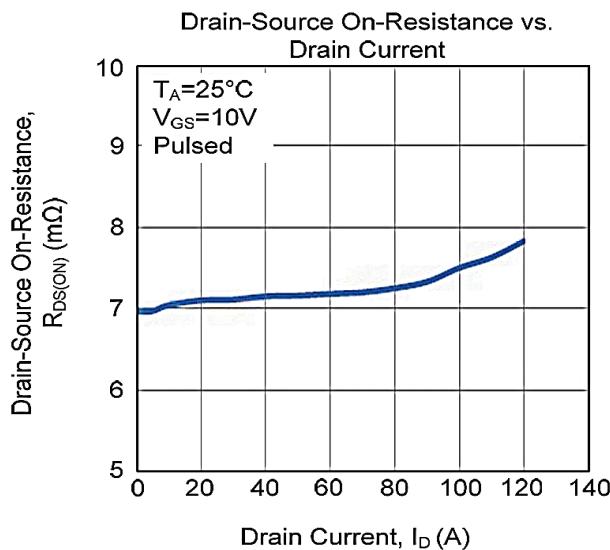
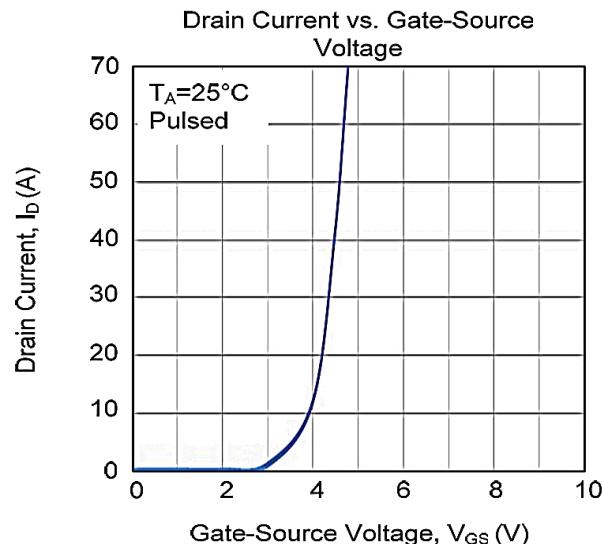
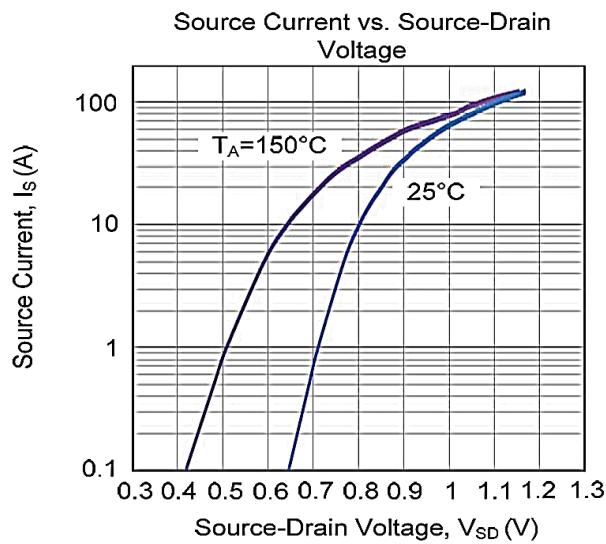




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■ TYPICAL CHARACTERISTICS(2)

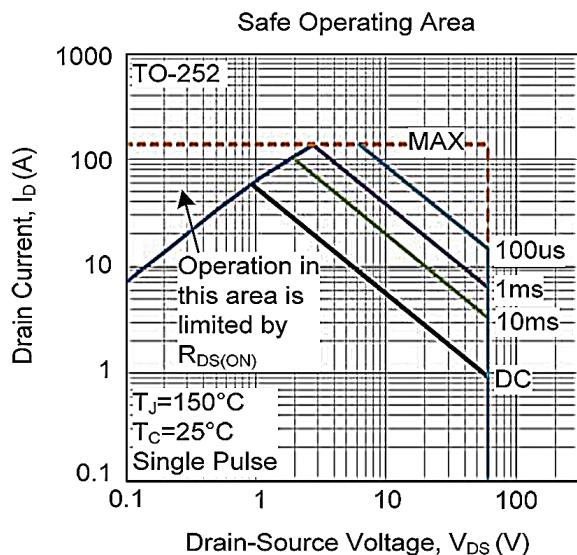




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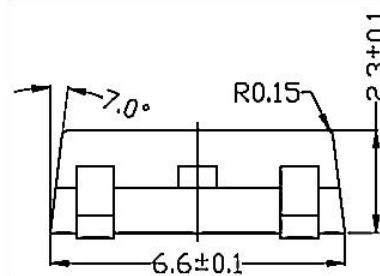
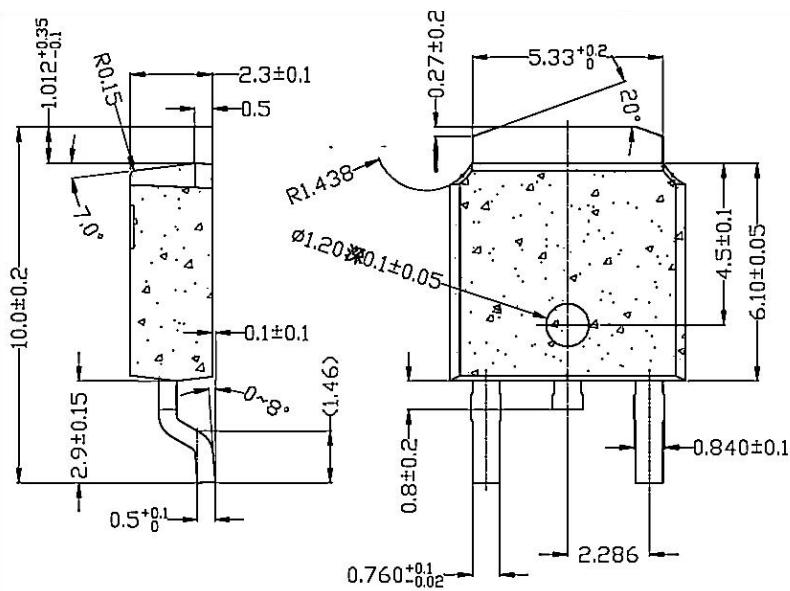
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■ TYPICAL CHARACTERISTICS(Con.t)

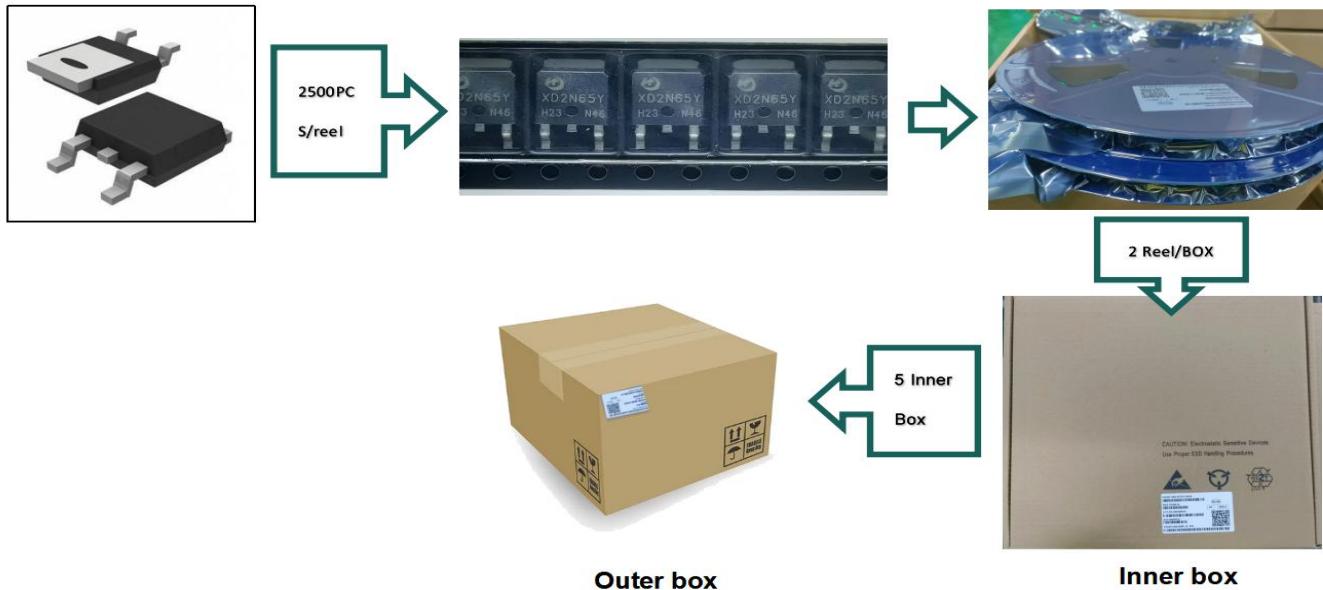




## ■ TO - 252 PACKAGE OUTLINE DIMENSIONS



## ■ TO - 252 PACKING INFORMATION



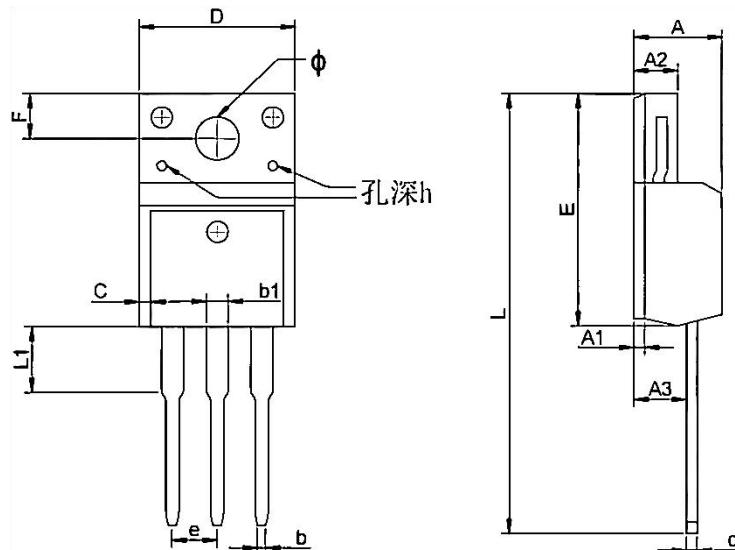
Package version	Reel dimensions $\phi \times H$ (mm)	Per Reel (pcs)	Reels per box	Inner box dimensions L×W×H (mm)	Outer box (pcs)	Outer box dimensions L×W×H (mm)
T0-252	$\phi 330 \times 20$	2500	2	360*340*50	25000	375*375*280



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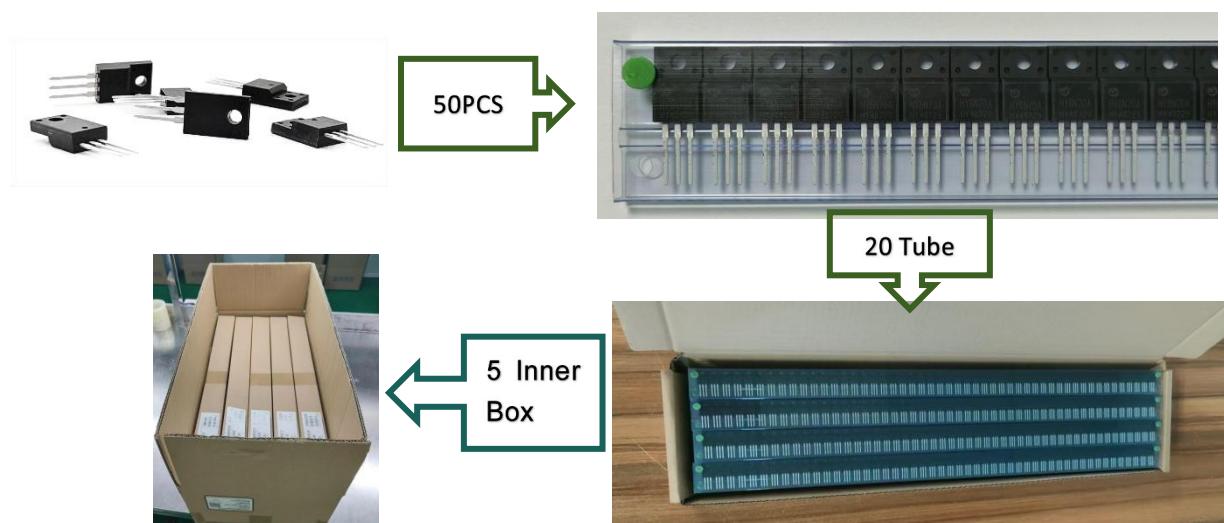
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## ■ TO- 220F PACKAGE OUTLINE DIMENSIONS



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max	Min	Max
A	4.300	4.750	0.169	0.185
A1	1.830	REF	0.072	REF
A2	2.300	2.850	0.090	0.112
A3	2.500	2.900	0.098	0.114
b	0.400	0.420	0.016	0.016
b1	1.220	1.280	0.048	0.050
C	0.690	0.720	0.027	0.028
c	0.490	0.510	0.019	0.020
D	9.960	10.200	0.392	0.400
E	15.000	15.950	0.588	0.625
e	2.574	TYP	0.101	TYP
F	3.470	REF	0.136	REF
y	3.200	REF	0.125	REF
h	0.000	0.300	0.000	0.012
L	28.780	28.900	1.128	1.133
L1	2.990	3.100	0.117	0.122

## ■ TO - 220F PACKING INFORMATION



Package version	Tube dimensions LxWxH (mm)	Outer Box Per Tube (pcs)	Tube per box	Inner box dimensions LxWxH (mm)	PCS/Inner box	Outer box dimensions LxWxH(mm)	Inner Box PCS/Outer box
TO-220F	530*32*7	50	20	580*155*50	1000	602*277*188	5000